

ABSTRACT OF THE DISCLOSURE

A board for testing DVD (Digital Versatile Disc) ROM (Read Only Memory) chipset and associated circuit for generating radio frequency signals with phase difference are provided. The circuit includes signal potential dividers, high pass filters, and a phase shifter. The circuit receives a digital input signal, which has a predetermined frequency, generated by a chip test device. The radio frequency signals with phase difference for testing the analog circuit block of DVD ROM chipset are generated according to the received digital input signal. Therefor, the high temperature operating life test for optical disc drive chips can be achieved.